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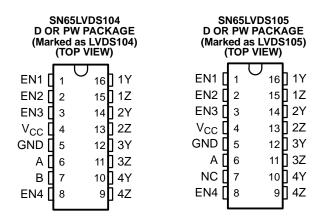
4-PORT LVDS AND 4-PORT TTL-TO-LVDS REPEATERS

FEATURES

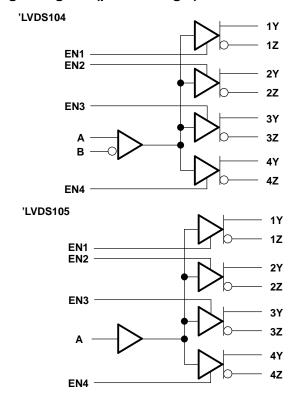
- Receiver and Drivers Meet or Exceed the Requirements of ANSI EIA/TIA-644 Standard
 - SN65LVDS105 Receives Low-Voltage TTL (LVTTL) Levels
 - SN65LVDS104 Receives Differential Input Levels. ±100 mV
- Typical Data Signaling Rates to 400 Mbps or **Clock Frequencies to 400 MHz**
- Operates From a Single 3.3-V Supply
- Low-Voltage Differential Signaling With Typical Output Voltage of 350 mV and a 100- Ω Load
- **Propagation Delay Time**
 - SN65LVDS105 2.2 ns (Typ)
 - SN65LVDS104 3.1 ns (Typ)
- **LVTTL Levels Are 5-V Tolerant**
- **Electrically Compatible With LVDS, PECL,** LVPECL, LVTTL, LVCMOS, GTL, BTL, CTT. SSTL, or HSTL Outputs With External **Networks**
- **Driver Outputs Are High Impedance When** Disabled or With V_{CC} <1.5 V
- **Bus-Pin ESD Protection Exceeds 16 kV**
- **SOIC and TSSOP Packaging**

DESCRIPTION

The SN65LVDS104 and SN65LVDS105 are a differential line receiver and a LVTTL input (respectively) connected to four differential line drivers that implement the electrical characteristics of low-voltage differential signaling (LVDS). LVDS, as specified in EIA/TIA-644 is a data signaling technique that offers low-power, low-noise coupling, and switching speeds to transmit data at relatively long distances. (Note: The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media, the noise coupling to the environment, and other system characteristics.)



logic diagram (positive logic)



The intended application of this device and signaling technique is for point-to-point baseband data transmission over controlled impedance media of approximately 100 Ω. The transmission media may be printed-circuit board traces, backplanes, or cables. Having the drivers integrated into the same substrate, along with the low pulse skew of balanced signaling, allows extremely precise timing alignment of the signals repeated from the input. This is particularly advantageous in distribution or expansion of signals such as clock or serial data stream.



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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DESCRIPTION (CONTINUED)

The SN65LVDS104 and SN65LVDS105 are characterized for operation from -40°C to 85°C.

The SN65LVDS104 and SN65LVDS105 are members of a family of LVDS repeaters. A brief overview of the family is provided in the table below.

Selection Guide to LVDS Repeaters

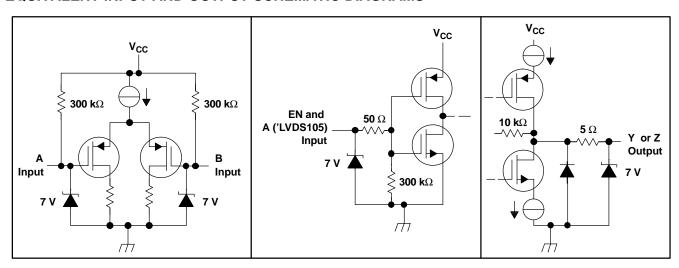
DEVICE	NO. INPUTS	NO. OUTPUTS	PACKAGE	COMMENT
SN65LVDS22	2 LVDS	2 LVDS	16-pin D	Dual multiplexed LVDS repeater
SN65LVDS104	1 LVDS	4 LVDS	16-pin D	4-Port LVDS repeater
SN65LVDS105	1 LVTTL	4 LVDS	16-pin D	4-Port TTL-to-LVDS repeater
SN65LVDS108	1 LVDS	8 LVDS	38-pin DBT	8-Port LVDS repeater
SN65LVDS109	2 LVDS	8 LVDS	38-pin DBT	Dual 4-port LVDS repeater
SN65LVDS116	1 LVDS	16 LVDS	64-pin DGG	16-Port LVDS repeater
SN65LVDS117	2 LVDS	16 LVDS	64-pin DGG	Dual 8-port LVDS repeater

Function Tables⁽¹⁾

SN65LVDS104					SN65LVDS105				
INPUT		OUT	PUT	INF	PUT	OUTPUT			
$V_{ID} = V_A - V_B$	xEN	xΥ	χZ	Α	ENx	xΥ	χZ		
X	Х	Z	Z	L	Н	L	Н		
X	L	Z	Z	Н	Н	Н	L		
V _{ID} ≥ 100 mV	Н	Н	L	Open	Н	L	Н		
-100 mV < V _{ID} < 100 mV	Н	?	?	Х	L	Z	Z		
$V_{ID} \le -100 \text{ mV}$	Н	L	Н	Х	X	Z	Z		

(1) H = high level, L = low level, Z = high impedance, ? = indeterminate, X = don't care

EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS





ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted) (1)

		UNIT
Supply voltage range, V _{CC} (2)	-0.5 to 4 V	
Valtage ronge	Enables, A ('LVDS105)	-0.5 to 6 V
Voltage range	A, B, Y or Z	-0.5 to 4 V
Electrostatic discharge (3)	A, B, Y, Z, and GND	Class 3, A:16 kV, B: 400 V
Continuous power dissipation		See Dissipation Rating Table
Storage temperature range		−65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds		260°C

⁽¹⁾ Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C POWER RATING	OPERATING FACTOR ⁽¹⁾ ABOVE T _A = 25°C	T _A = 85°C POWER RATING
D	950 mW	7.6 mW/°C	494 mW
PW	774 mW	6.2 mW/°C	402 mW

⁽¹⁾ This is the inverse of the junction-to-ambient thermal resistance when board-mounted (low-k) and with no air flow.

RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	3	3.3	3.6	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
V _I or V _{IC}	Voltage at any bus terminal (separately or common-mode)	0		V _{CC} -0.8	
T _A	Operating free-air temperature	-40		85	°C

⁽²⁾ All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

⁽³⁾ Tested in accordance with MIL-STD-883C Method 3015.7



SN65LVDS104 ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IT+}	Positive-going differential input voltage threshold	ge threshold			100	\/
V _{IT-}	Negative-going differential input voltage threshold	See Figure 1 and Table 1	-100			mV
V _{OD}	Differential output voltage magnitude	D 400 O \/ \ \ \ 100 m\/	247	340	454	
Δ V _{OD}	Change in differential output voltage magnitude between logic states	$R_L = 100 \Omega$, $V_{ID} = \pm 100 \text{ mV}$, See Figure 1 and Figure 2	-50		50	mV
V _{OC(SS)}	Steady-state common-mode output voltage		1.125		1.375	V
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage between logic states	See Figure 3	-50		50	mV
V _{OC(PP)}	Peak-to-peak common-mode output voltage	=		25	150	mV
	Complex assument	Enabled, $R_L = 100 \Omega$		23	35	mA
I _{CC}	Supply current	Disabled		3	8	mA
-	land surrent (A or D invote)	V _I = 0 V	-2	-11	-20	
I _I	Input current (A or B inputs)	V _I = 2.4 V	-1.2	-3		μA
I _{I(OFF)}	Power-off Input current	$V_{CC} = 1.5 \text{ V}, V_I = 2.4 \text{ V}$			20	μΑ
I _{IH}	High-level input current (enables)	V _{IH} = 2 V			20	μΑ
I _{IL}	Low-level input current (enables)	V _{IL} = 0.8 V			10	μΑ
	Chart aircuit autaut aurrent	V _{OY} or V _{OZ} = 0 V			±10	mA
los	Short-circuit output current	V _{OD} = 0 V			±10	mA
l _{oz}	High-impedance output current	V _O = 0 V or 2.4 V			±1	μΑ
I _{O(OFF)}	Power-off output current	$V_{CC} = 1.5 \text{ V}, V_{O} = 2.4 \text{ V}$			±1	μA
C _{IN}	Input capacitance (A or B inputs)	$V_I = 0.4 \sin (4E6\pi t) + 0.5 V$		3		pF
Co	Output capacitance (Y or Z outputs)	$V_1 = 0.4 \sin (4E6\pi t) + 0.5 V$, Disabled		9.4		pF

⁽¹⁾ All typical values are at 25°C and with a 3.3-V supply.

SN65LVDS104 SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output		2.4	3.2	4.2	ns
t _{PHL}	Propagation delay time, high-to-low-level output		2.2	3.1	4.2	ns
t _r	Differential output signal rise time	$R_1 = 100 \Omega, C_1 = 10 pF,$	0.3	0.8	1.2	ns
t _f	Differential output signal fall time	See Figure 4	0.3	0.8	1.2	ns
t _{sk(p)}	Pulse skew (t _{PHL} - t _{PLH})			150	500	ps
t _{sk(o)}	Channel-to-channel output skew ⁽²⁾			20	100	ps
t _{sk(pp)}	Part-to-part skew ⁽³⁾				1.5	ns
t _{PZH}	Propagation delay time, high-impedance-to-high-level output			7.2	15	ns
t _{PZL}	Propagation delay time, high-impedance-to-low-level output	Coo Figure F		8.4	15	ns
t _{PHZ}	Propagation delay time, high-level-to-high-impedance output	See Figure 5		3.6	15	ns
t _{PLZ}	Propagation delay time, low-level-to-high-impedance output			6	15	ns

All typical values are at 25°C and with a 3.3-V supply.

 $t_{sk(0)}$ is the magnitude of the time difference between the t_{PLH} or t_{PHL} of all drivers of a single device with all of their inputs connected together.

 $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.



SN65LVDS105 ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{OD}	Differential output voltage magnitude	$R_L = 100 \Omega$,	247	340	454	
$\Delta V_{OD} $	Change in differential output voltage magnitude between logic states	$V_{ID} = \pm 100 \text{ mV},$ See Figure 6 and Figure 7	-50		50	mV
V _{OC(SS)}	Steady-state common-mode output voltage		1.125		1.37 5	V
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage between logic states	See Figure 8	-50		50	mV
$V_{OC(PP)}$	Peak-to-peak common-mode output voltage			25	150	mV
	Cumply ourrent	Enabled, $R_L = 100 \Omega$		23	35	mA
I _{CC}	Supply current	Disabled		0.7	6.4	mA
I _{IH}	High-level input current	V _{IH} = 2 V			20	μΑ
I _{IL}	Low-level input current	V _{IL} = 0.8 V			10	μΑ
	Chart sireuit autaut aureat	V_{OY} or $V_{OZ} = 0 V$			±10	mA
los	Short-circuit output current	V _{OD} = 0 V			±10	mA
I _{OZ}	High-impedance output current	V _O = 0 V or 2.4 V			±1	μΑ
I _{O(OFF)}	Power-off output current	$V_{CC} = 1.5 \text{ V}, V_{O} = 2.4 \text{ V}$		0.3	±1	μΑ
C _{IN}	Input capacitance	$V_I = 0.4 \sin (4E6\pi t) + 0.5 V$		5		pF
Co	Output capacitance (Y or Z outputs)	$V_I = 0.4 \sin (4E6\pi t) + 0.5 V$, Disabled		9.4		pF

⁽¹⁾ All typical values are at 25°C and with a 3.3-V supply.

SN65LVDS105 SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output		1.7	2.2	3	ns
t _{PHL}	Propagation delay time, high-to-low-level output		1.4	2.3	3.5	ns
t _r	Differential output signal rise time	$R_L = 100 \Omega, C_L = 10 pF,$	0.3	0.8	1.2	ns
t _f	Differential output signal fall time	See Figure 9	0.3	0.8	1.2	ns
t _{sk(p)}	Pulse skew (t _{PHL} - t _{PLH})			150	500	ps
t _{sk(o)}	Channel-to-channel output skew ⁽²⁾			20	100	ps
t _{sk(pp)}	Part-to-part skew ⁽³⁾				1.5	ns
t _{PZH}	Propagation delay time, high-impedance-to-high-level output			7.2	15	ns
t_{PZL}	Propagation delay time, high-impedance-to-low-level output	Soo Figure 10		8.4	15	ns
t _{PHZ}	Propagation delay time, high-level-to-high-impedance output	See Figure 10		3.6	15	ns
t_{PLZ}	Propagation delay time, low-level-to-high-impedance output			6	15	ns

All typical values are at 25°C and with a 3.3-V supply. $t_{sk(o)}$ is the magnitude of the time difference between the t_{PLH} or t_{PHL} of all drivers of a single device with all of their inputs connected together. (2)

 $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.



PARAMETER MEASUREMENT INFORMATION

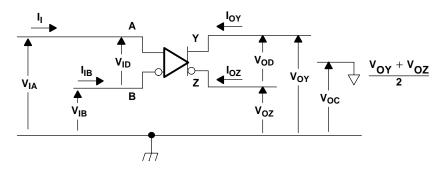


Figure 1. 'LVDS104 Voltage and Current Definitions

Table 1. SN65LVDS104 Minimum and Maximum Input Threshold Test Voltages

APPLIED VOLTAGES		DIEEEDENTIAL		
VIA	V _{IB}	V _{ID}	V _{IC}	
1.25 V	1.15 V	100 mV	1.2 V	
1.15 V	1.25 V	–100 mV	1.2 V	
2.4 V	2.3 V	100 mV	2.35 V	
2.3 V	2.4 V	–100 mV	2.35 V	
0.1 V	0 V	100 mV	0.05 V	
0 V	0.1 V	–100 mV	0.05 V	
1.5 V	0.9 V	600 mV	1.2 V	
0.9 V	1.5 V	−600 mV	1.2 V	
2.4 V	1.8 V	600 mV	2.1 V	
1.8 V	2.4 V	–600 mV	2.1 V	
0.6 V	0 V	600 mV	0.3 V	
0 V	0.6 V	–600 mV	0.3 V	

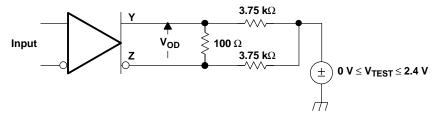
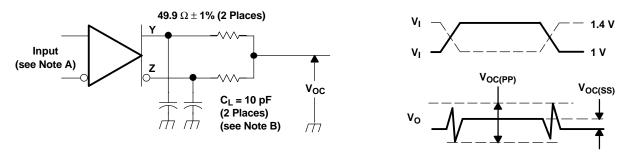


Figure 2. 'LVDS104 $V_{\rm OD}$ Test Circuit

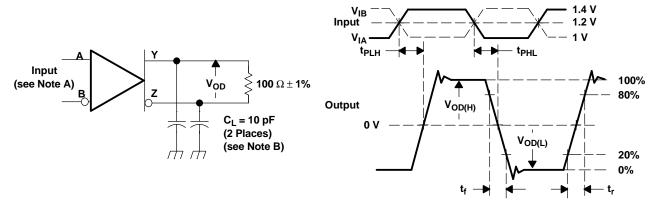
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- A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_r \le 1$ ns, pulse repetition rate (PRR) = 0.5 Mpps, pulsewidth = 500 ± 10 ns.
- B. C_L includes instrumentation and fixture capacitance within 0,06 m of the D.U.T. The measurement of V_{OC(PP)} is made on test equipment with a –3 dB bandwidth of at least 300 MHz.

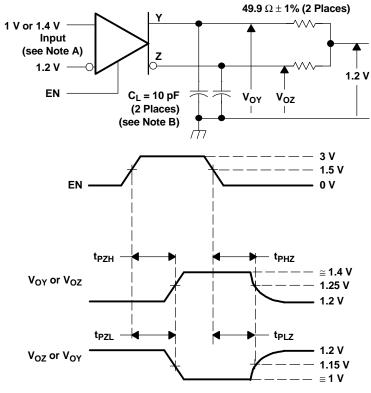
Figure 3. 'LVDS104 Test Circuit and Definitions for the Driver Common-Mode Output Voltage



- A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \le 1$ ns, pulse repetition rate (PRR) = 50 Mpps, pulsewidth = 10 ± 0.2 ns.
- B. C_L includes instrumentation and fixture capacitance within 0,06 m of the D.U.T.

Figure 4. 'LVDS104 Test Circuit, Timing, and Voltage Definitions for the Differential Output Signal





- A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \le 1$ ns, pulse repetition rate (PRR) = 0.5 Mpps, pulsewidth = 500 ± 10 ns.
- B. C_L includes instrumentation and fixture capacitance within 0,06 m of the D.U.T.

Figure 5. 'LVDS104 Enable and Disable Time Circuit and Definitions

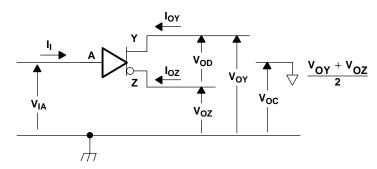


Figure 6. 'LVDS105 Voltage and Current Definitions

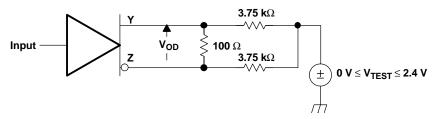
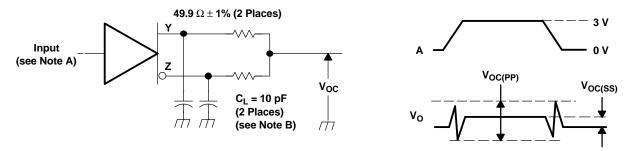


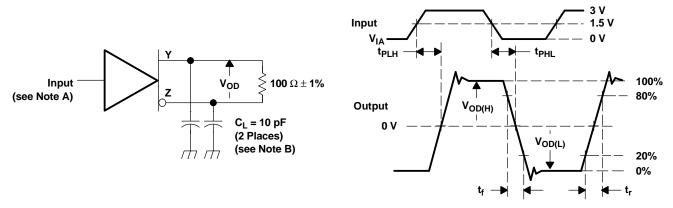
Figure 7. 'LVDS105 VOD Test Circuit





- A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_r \le 1$ ns, pulse repetition rate (PRR) = 0.5 Mpps, pulsewidth = 500 ± 10 ns.
- B. C_L includes instrumentation and fixture capacitance within 0,06 m of the D.U.T. The measurement of V_{OC(PP)} is made on test equipment with a -3 dB bandwidth of at least 300 MHz.

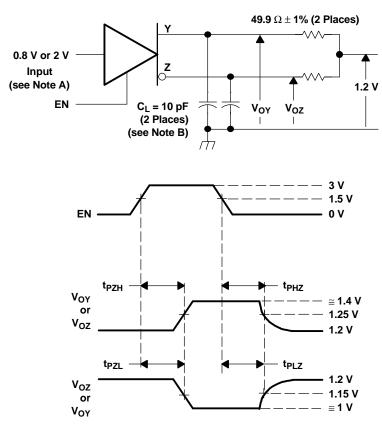
Figure 8. 'LVDS105 Test Circuit and Definitions for the Driver Common-Mode Output Voltage



- A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_r \le 1$ ns, pulse repetition rate (PRR) = 50 Mpps, pulsewidth = 10 ± 0.2 ns.
- B. C_L includes instrumentation and fixture capacitance within 0,06 m of the D.U.T.

Figure 9. 'LVDS105 Test Circuit, Timing, and Voltage Definitions for the Differential Output Signal



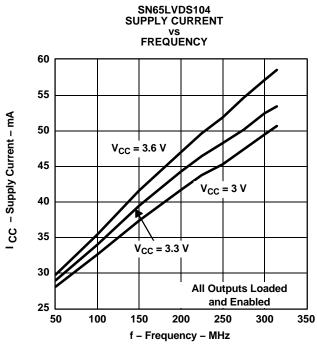


- A. All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \le 1$ ns, pulse repetition rate (PRR) = 0.5 Mpps, pulsewidth = 500 ± 10 ns.
- B. $\,$ C_L includes instrumentation and fixture capacitance within 0,06 m of the D.U.T.

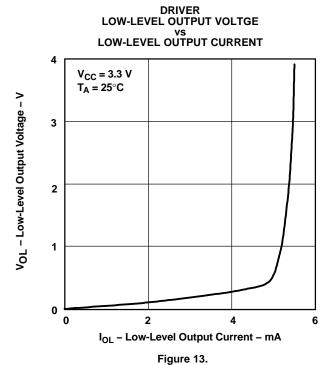
Figure 10. 'LVDS105 Enable and Disable Time Circuit and Definitions



TYPICAL CHARACTERISTIC

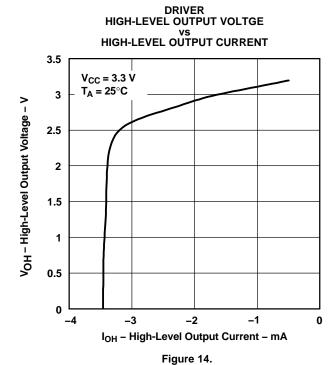






SN65LVDS105 SUPPLY CURRENT vs FREQUENCY 50 45 I CC - Supply Current - mA 40 V_{CC} = 3.6 V 35 $V_{CC} = 3 V$ 30 V_{CC} = 3.3 V 25 **All Outputs Loaded** and Enabled 20 100 150 200 250 300 350 50 f - Frequency - MHz

Figure 12.





TYPICAL CHARACTERISTIC (continued)



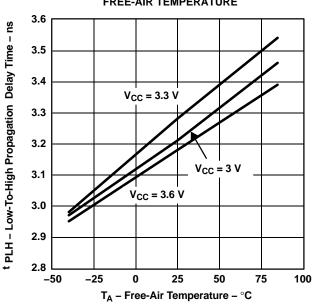


Figure 15.

SN65LVDS104 HIGH-TO-LOW PROPAGATION DELAY TIME VS FREE-AIR TEMPERATURE

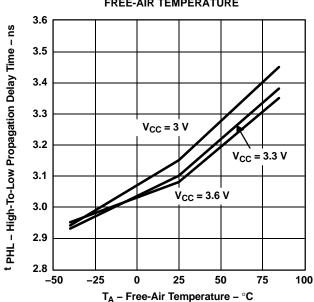


Figure 16.

SN65LVDS105 LOW-TO-HIGH PROPAGATION DELAY TIME

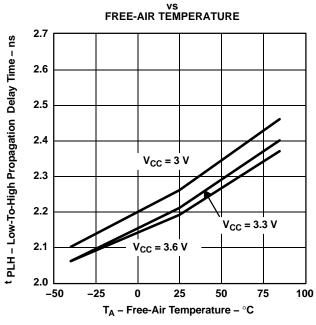


Figure 17.

SN65LVDS105 HIGH-TO-LOW PROPAGATION DELAY TIME VS FREE-AIR TEMPERATURE

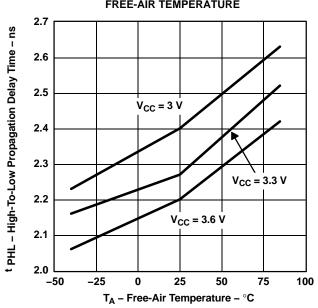
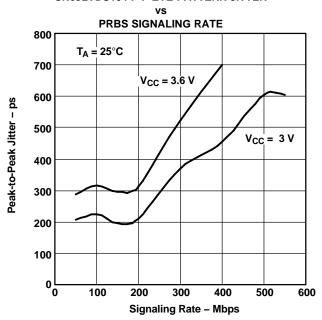


Figure 18.



TYPICAL CHARACTERISTIC (continued)

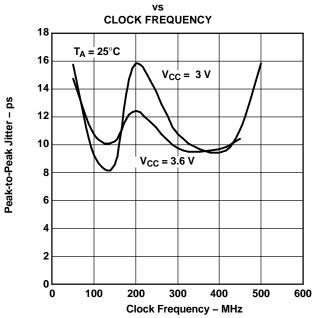
SN65LVDS104 P-P EYE-PATTERN JITTER



NOTES: Input: 2¹⁵ PRBS with peak-to-peak jitter <115 ps at 100 Mbps. Test board adds about 70 ps p-p jitter. All outputs enabled and loaded with differential 100-Ω loads, worst-case output, supply decoupled with 0.1-μF ceramic 0603-style capacitors 1 cm from the device.

Figure 19.

SN65LVDS104 P-P PERIOD JITTER



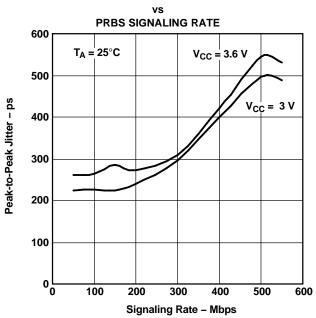
NOTES: Input: 50% duty cycle square wave with period jitter < 9 ps at 100 MHz. Test board adds about 5 ps p-p jitter. All outputs enabled and loaded with differential 100- Ω loads, worst-case output, supply decoupled with 0.1- μ F and 0.001- μ F ceramic 0603-style capacitors 1 cm from the device.

Figure 20.



TYPICAL CHARACTERISTIC (continued)

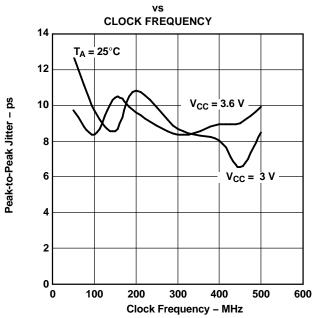
SN65LVDS105 P-P EYE-PATTERN JITTER



NOTES: Input: 2^{15} PRBS with peak-to-peak Jitter < 147 ps at 100 Mbps, Test board adds about 43 ps p-p jitter. All outputs enabled and loaded with differential 100- Ω loads, worst-case output, supply decoupled with 0.1- μ F and 0.001- μ F ceramic 0603-style capacitors 1 cm from the device.

Figure 21.

SN65LVDS105 P-P PERIOD JITTER



NOTES: Input: 50% duty cycle square wave with period jitter < 10 ps at 100 MHz. Test board adds about 5 ps p-p jitter. All outputs enabled and loaded with differential 100-Ω loads, worst-case output, supply decoupled with 0.1-μF and 0.001-μF ceramic 0603-style capacitors 1 cm from the device.

Figure 22.



APPLICATION INFORMATION

INPUT LEVEL TRANSLATION

An LVDS receiver can be used to receive various other types of logic signals. Figure 23 through Figure 32 show the termination circuits for SSTL, HSTL, GTL, BTL, LVPECL, PECL, CMOS, and TTL.

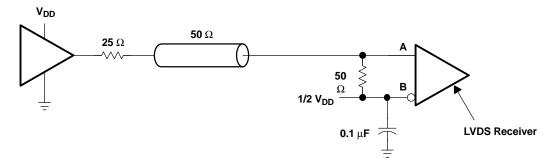


Figure 23. Stub-Series Terminated (SSTL) or High-Speed Transceiver Logic (HSTL)

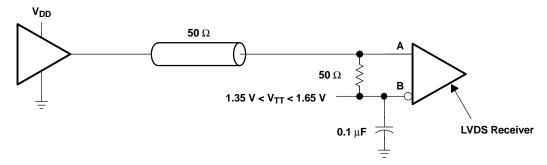


Figure 24. Center-Tap Termination (CTT)

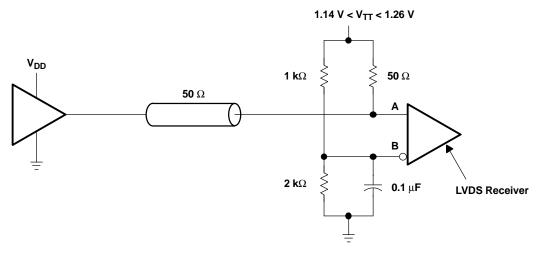


Figure 25. Gunning Transceiver Logic (GTL)



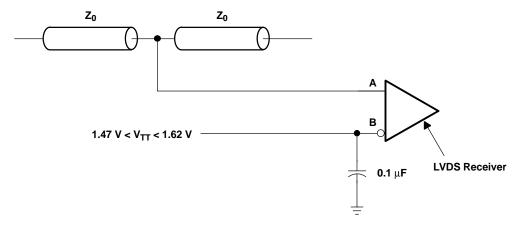


Figure 26. Backplane Transceiver Logic (BTL)

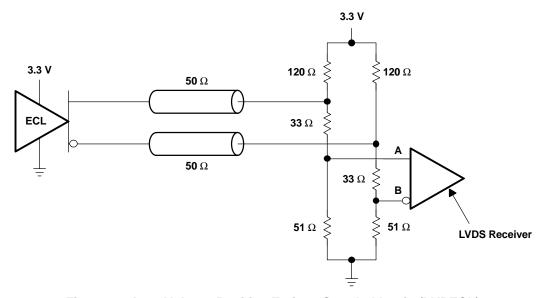


Figure 27. Low-Voltage Positive Emitter-Coupled Logic (LVPECL)



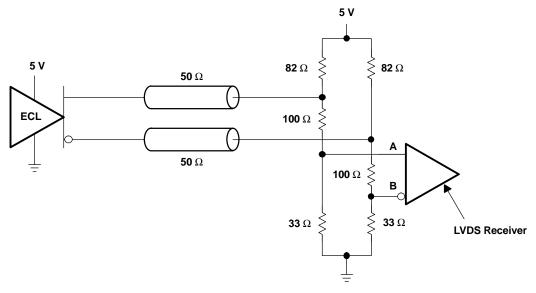


Figure 28. Positive Emitter-Coupled Logic (PECL)

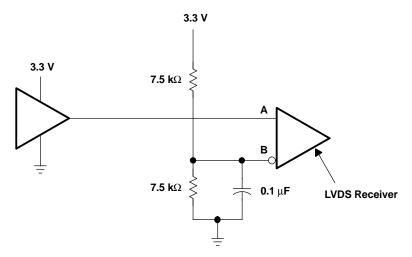


Figure 29. 3.3-V CMOS



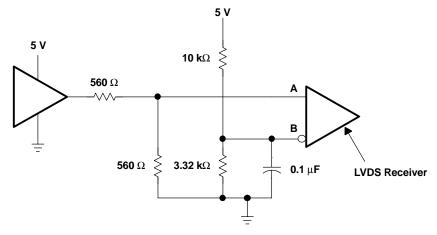


Figure 30. 5-V CMOS

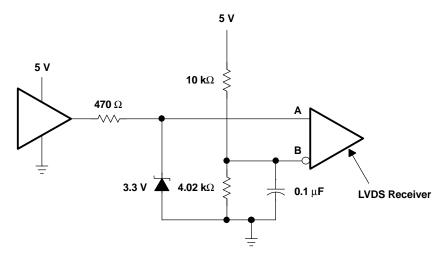


Figure 31. 5-V TTL

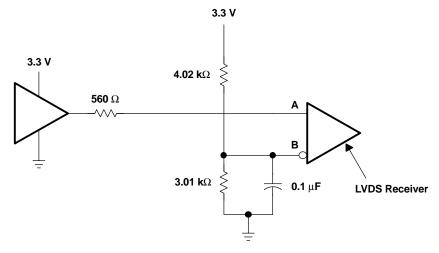


Figure 32. LVTTL



FAIL SAFE

A common problem with differential signaling applications is how the system responds when no differential voltage is present on the signal pair. The LVDS receiver is like most differential line receivers, in that its output logic state can be indeterminate when the differential input voltage is between –100 mV and 100 mV and within its recommended input common-mode voltage range. Hovever, TI LVDS receivers handles the open-input circuit situation differently.

Open-circuit means that there is little or no input current to the receiver from the data line itself. This could be when the driver is in a high-impedance state or the cable is disconnected. When this occurs, the LVDS receiver pulls each line of the signal pair to near V_{CC} through 300-k Ω resistors as shown in Figure 33. The fail-safe feature uses an AND gate with input voltage thresholds at about 2.3 V to detect this condition and force the output to a high-level regardless of the differential input voltage.

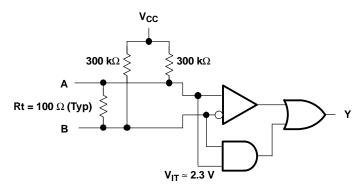


Figure 33. Open-Circuit Fail Safe of the LVDS Receiver

It is only under these conditions that the output of the receiver will be valid with less than a 100 mV differential input voltage magnitude. The presence of the termination resistor, Rt, does not affect the fail-safe function as long as it is connected as shown in Figure 33. Other termination circuits may allow a dc current to ground that could defeat the pullup currents from the receiver and the fail-safe feature.





i.com 8-Jan-2007

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
SN65LVDS104D	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS104DG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS104DR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS104DRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS104PW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS104PWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS104PWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS104PWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS105D	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS105DG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS105DR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS105DRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS105PW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS105PWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS105PWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
SN65LVDS105PWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.



PACKAGE OPTION ADDENDUM

8-Jan-2007

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

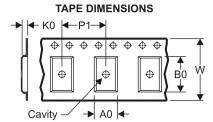
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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65LVDS104DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN65LVDS104PWR	TSSOP	PW	16	2000	330.0	12.4	7.0	5.6	1.6	8.0	12.0	Q1
SN65LVDS105DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN65LVDS105PWR	TSSOP	PW	16	2000	330.0	12.4	7.0	5.6	1.6	8.0	12.0	Q1





*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65LVDS104DR	SOIC	D	16	2500	346.0	346.0	33.0
SN65LVDS104PWR	TSSOP	PW	16	2000	346.0	346.0	29.0
SN65LVDS105DR	SOIC	D	16	2500	346.0	346.0	33.0
SN65LVDS105PWR	TSSOP	PW	16	2000	346.0	346.0	29.0

PW (R-PDSO-G**)

14 PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

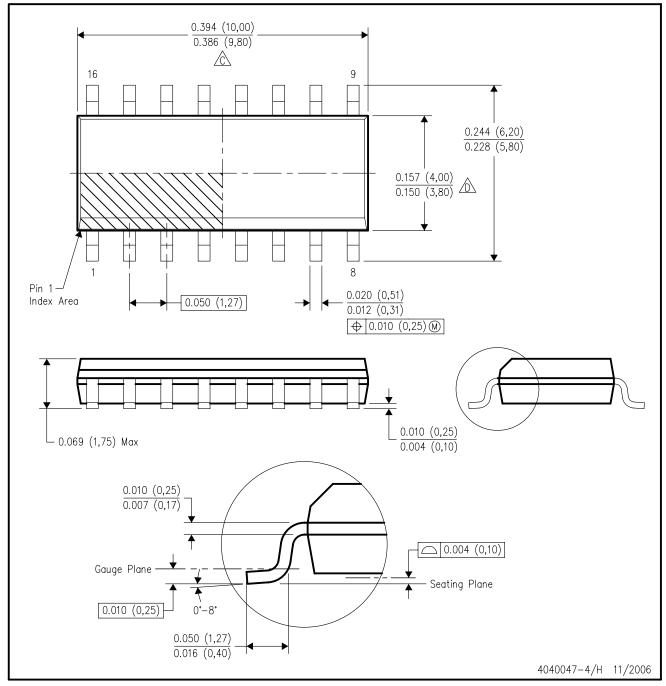
B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

D (R-PDSO-G16)

PLASTIC SMALL-OUTLINE PACKAGE

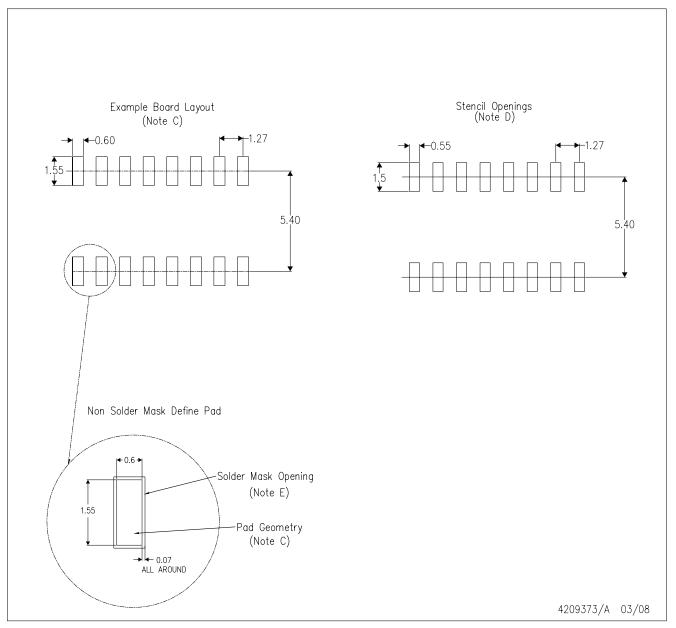


NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 (0,15) per end.
- Body width does not include interlead flash. Interlead flash shall not exceed .017 (0,43) per side.
- E. Reference JEDEC MS-012 variation AC.



D(R-PDSO-G16)



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Refer to IPC7351 for alternate board design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC—7525
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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